

Notice of References CitedApplication/Control No.
09/931,104Applicant(s)/Patent Under
Reexamination
YOSHIDA, EIJIExaminer
Johannes P. MondtArt Unit
2826

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,940,545 /	08-1999	Kash et al.	382/312
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Tsang, James C., Kash, Jeffrey Alan, and Vallet, David P., "Time-Resolved Optical Characterization of Electrical Activity in Integrated Circuits", Proceedings of the IEEE, Vol. 88, No. 9, September 2000.
	V	Wai Mun Yee, et al, "Laser Voltage Probe (LVP): a novel optical probing technology for flip-chip packaged microprocessors", in Proc. of the 1999 7 th Int. Symp. on the Physical and failure Analysis of Integrated Circuits, 5-9 July '99, Singapore.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.